



STGW30NB60HD

N-CHANNEL 30A - 600V TO-247 PowerMESH™ IGBT

TYPE	V _{CES}	V _{CE(sat)}	I _C
STGW30NB60HD	600 V	< 2.8 V	30 A

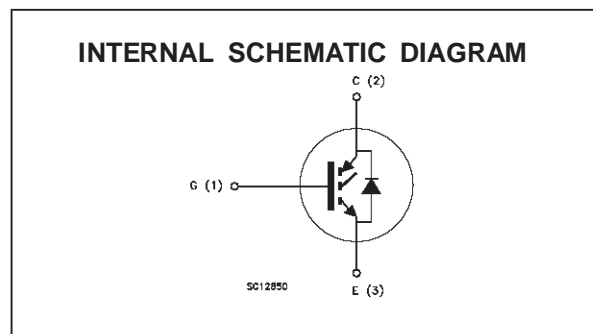
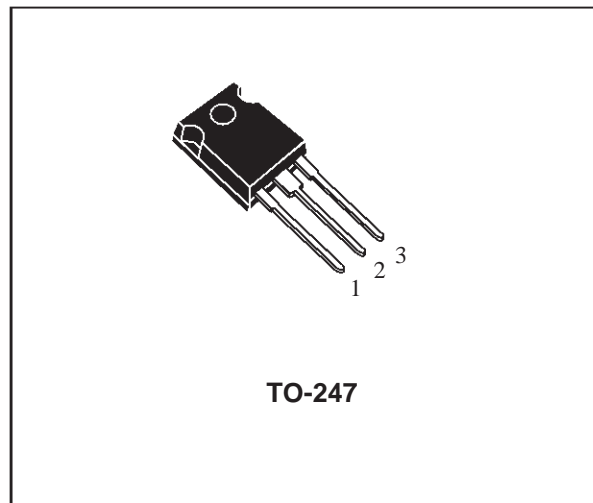
- HIGH INPUT IMPEDANCE (VOLTAGE DRIVEN)
- LOW ON-VOLTAGE DROP (V_{CESAT})
- LOW GATE CHARGE
- HIGH CURRENT CAPABILITY
- VERY HIGH FREQUENCY OPERATION
- OFF LOSSES INCLUDE TAIL CURRENT
- CO-PACKAGE WITH TURBOSWITCH™ ANTIPARALLEL DIODE

DESCRIPTION

Using the latest high voltage technology based on a patented strip layout, STMicroelectronics has designed an advanced family of IGBTs, the PowerMESH™ IGBTs, with outstanding performances. The suffix "H" identifies a family optimized to achieve very low switching times for high frequency applications (<120kHz).

APPLICATIONS

- HIGH FREQUENCY MOTOR CONTROLS
- WELDING EQUIPMENTS
- SMPS AND PFC IN BOTH HARD SWITCH AND RESONANT TOPOLOGIES



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{CES}	Collector-Emitter Voltage (V _{GS} = 0)	600	V
V _{ECR}	Emitter-Collector Voltage	20	V
V _{GE}	Gate-Emitter Voltage	± 20	V
I _C	Collector Current (continuous) at T _c = 25 °C	60	A
I _C	Collector Current (continuous) at T _c = 100 °C	30	A
I _{CM} (•)	Collector Current (pulsed)	240	A
P _{tot}	Total Dissipation at T _c = 25 °C	190	W
	Derating Factor	1.52	W/°C
T _{stg}	Storage Temperature	-65 to 150	°C
T _j	Max. Operating Junction Temperature	150	°C

(•) Pulse width limited by safe operating area

STGW30NB60HD

THERMAL DATA

$R_{thj-case}$	Thermal Resistance Junction-case	Max	0.66	$^{\circ}C/W$
$R_{thj-amb}$	Thermal Resistance Junction-ambient	Max	30	$^{\circ}C/W$
R_{thc-h}	Thermal Resistance Case- heatsink	Typ	0.1	$^{\circ}C/W$

ELECTRICAL CHARACTERISTICS ($T_j = 25^{\circ}C$ unless otherwise specified)

OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{BR(CES)}$	Collector-Emitter Breakdown Voltage	$I_C = 250 \mu A$ $V_{GE} = 0$	600			V
I_{CES}	Collector cut-off ($V_{GE} = 0$)	$V_{CE} = \text{Max Rating}$ $T_j = 25^{\circ}C$ $V_{CE} = \text{Max Rating}$ $T_j = 125^{\circ}C$			250 2000	μA μA
I_{GES}	Gate-Emitter Leakage Current ($V_{CE} = 0$)	$V_{GE} = \pm 20 V$ $V_{CE} = 0$			± 100	nA

ON (*)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{GE(th)}$	Gate Threshold Voltage	$V_{CE} = V_{GE}$ $I_C = 250 \mu A$	3		5	V
$V_{CE(SAT)}$	Collector-Emitter Saturation Voltage	$V_{GE} = 15 V$ $I_C = 30 A$ $V_{GE} = 15 V$ $I_C = 30 A$ $T_j = 125^{\circ}C$		2.2 1.8	2.8	V V

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
g_{fs}	Forward Transconductance	$V_{CE} = 25 V$ $I_C = 30 A$		20		S
C_{ies} C_{oes} C_{res}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{CE} = 25 V$ $f = 1 MHz$ $V_{GE} = 0$		2300 250 60		pF pF pF
Q_G Q_{GE} Q_{GC}	Total Gate Charge Gate-Emitter Charge Gate-Collector Charge	$V_{CE} = 480 V$ $I_C = 30 A$ $V_{GE} = 15 V$		150 15 72		nC nC nC
I_{CL}	Latching Current	$V_{clamp} = 480 V$ $R_G = 10 \Omega$ $T_j = 150^{\circ}C$	120			A

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ t_r	Delay Time Rise Time	$V_{CC} = 480 V$ $I_C = 30 A$ $V_{GE} = 15 V$ $R_G = 10 \Omega$		15 35		ns ns
$(di/dt)_{on}$	Turn-on Current Slope	$V_{CC} = 480 V$ $I_C = 30 A$ $R_G = 10 \Omega$ $V_{GE} = 15 V$		1000		A/ μs
E_{on}	Turn-on Switching Losses	$T_j = 125^{\circ}C$		1000		μJ

ELECTRICAL CHARACTERISTICS (continued)

SWITCHING OFF

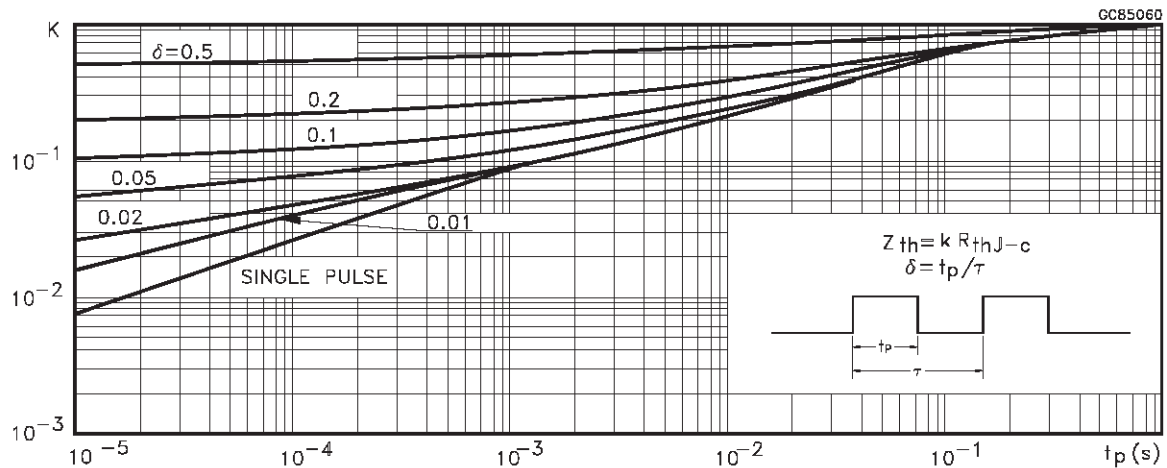
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
t_c	Cross-Over Time	$V_{CC} = 480\text{ V}$ $I_C = 30\text{ A}$ $R_{GE} = 10\ \Omega$ $V_{GE} = 15\text{ V}$		150		ns
$t_r(V_{off})$	Off Voltage Rise Time			40		ns
$t_{d(off)}$	Delay Time			210		ns
t_f	Fall Time			90		ns
$E_{off(**)}$	Turn-off Switching Loss			1.10		mJ
$E_{ts(\circ)}$	Total Switching Loss			2.0		mJ
t_c	Cross-Over Time	$V_{CC} = 480\text{ V}$ $I_C = 30\text{ A}$ $R_{GE} = 10\ \Omega$ $V_{GE} = 15\text{ V}$ $T_j = 125\text{ }^\circ\text{C}$		250		ns
$t_r(V_{off})$	Off Voltage Rise Time			70		ns
$t_{d(off)}$	Delay Time			250		ns
t_f	Fall Time			160		ns
$E_{off(**)}$	Turn-off Switching Loss			1.6		mJ
$E_{ts(\circ)}$	Total Switching Loss			2.65		mJ

COLLECTOR-EMITTER DIODE

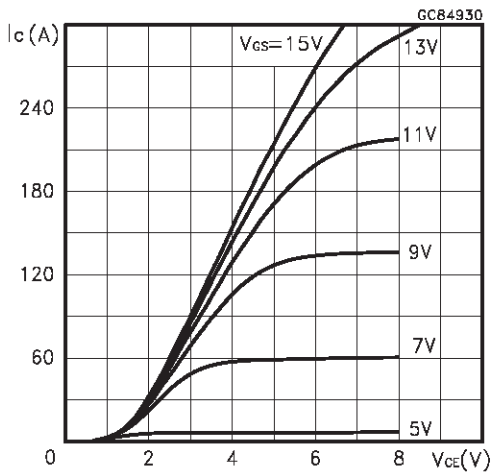
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I_f	Forward Current				30	A
I_{fm}	Forward Current pulsed				240	A
V_f	Forward On-Voltage	$I_f = 30\text{ A}$ $I_f = 30\text{ A}$ $T_j = 125\text{ }^\circ\text{C}$		1.7 1.55	2.0	V V
t_{rr}	Reverse Recovery Time	$I_f = 30\text{ A}$ $V_R = 100\text{ V}$ $di/dt = 100\text{ A}/\mu\text{S}$ $T_j = 125\text{ }^\circ\text{C}$		116		nS
Q_{rr}	Reverse Recovery Charge			406		nC
I_{rrm}	Reverse Recovery Current			7		A

- (●) Pulse width limited by max. junction temperature
- (○) Include recovery losses on the STTA2006 freewheeling diode
- (*) Pulsed: Pulse duration = 300 μs , duty cycle 1.5 %
- (**) Losses Include Also The Tail (Jedec Standardization)

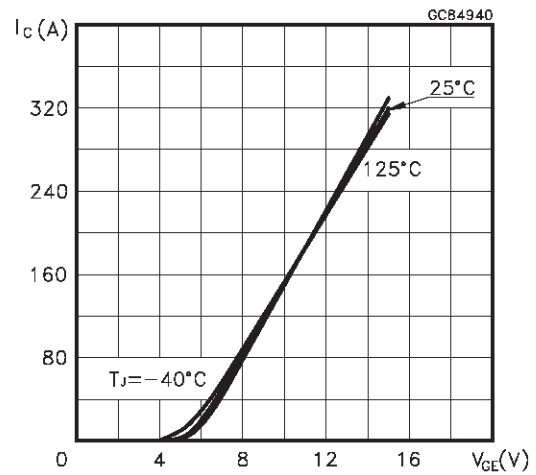
Thermal Impedance



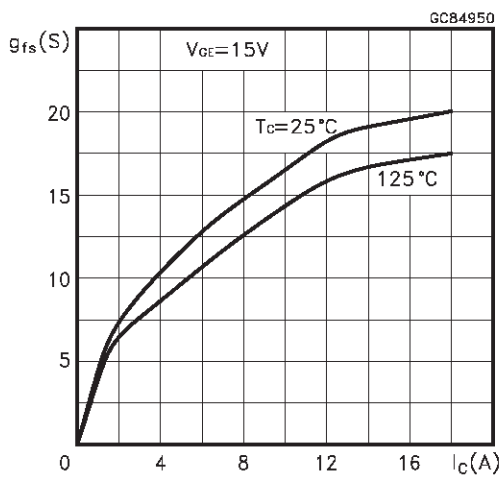
Output Characteristics



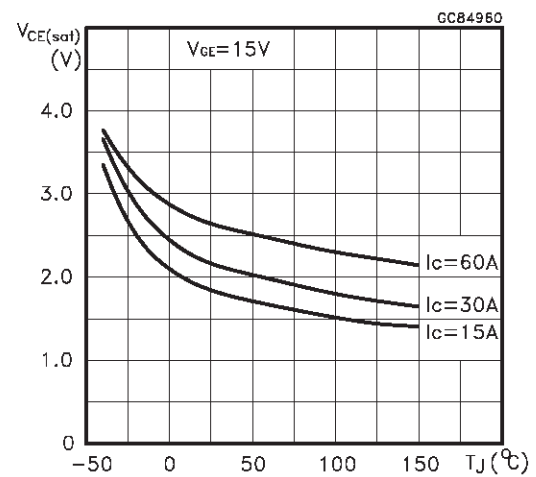
Transfer Characteristics



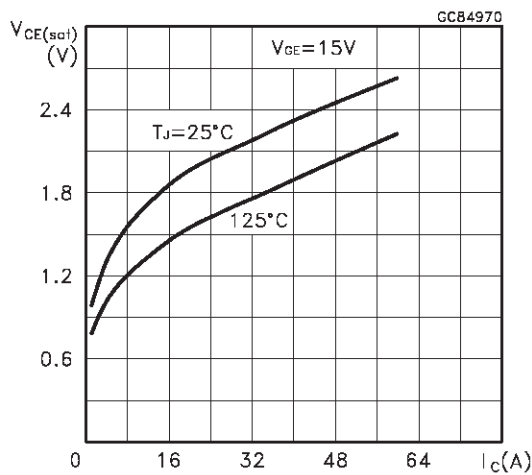
Transconductance



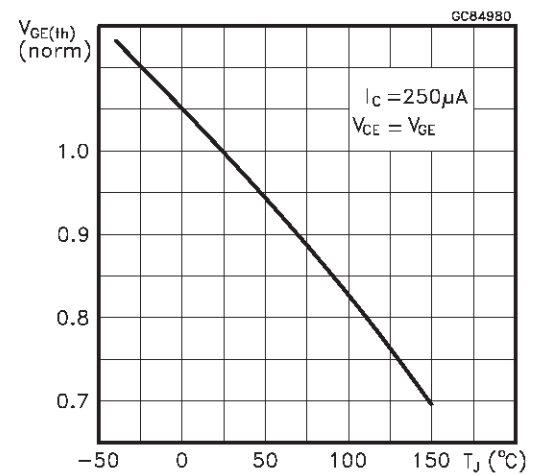
Collector-Emitter On Voltage vs Temperature



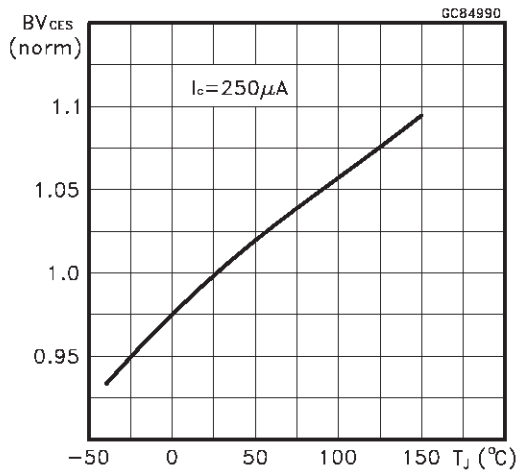
Collector-Emitter On Voltage vs Collector Current



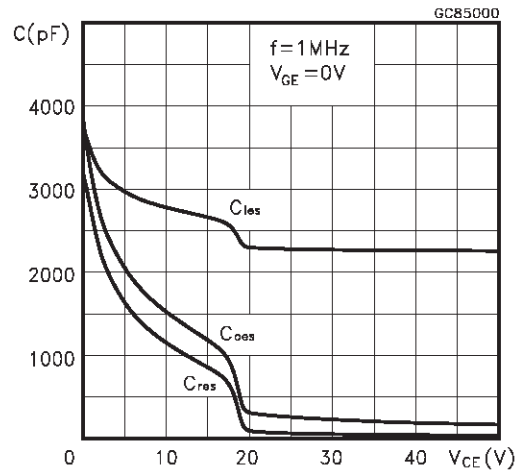
Gate Threshold vs Temperature



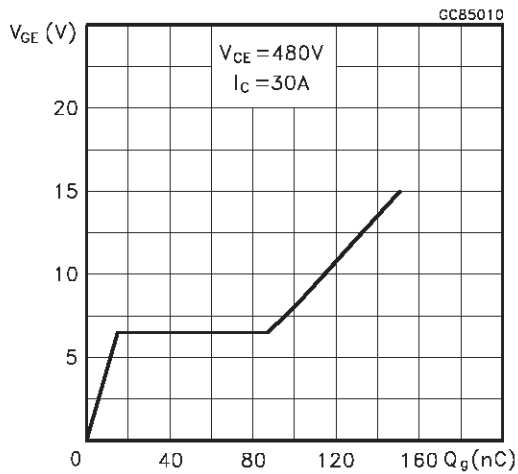
Normalized Breakdown Voltage vs Temperature



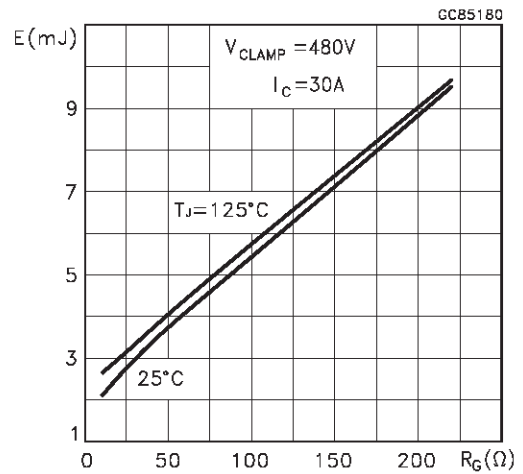
Capacitance Variations



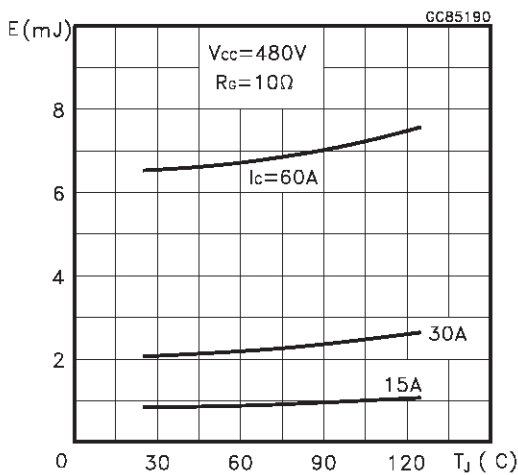
Gate Charge vs Gate-Emitter Voltage



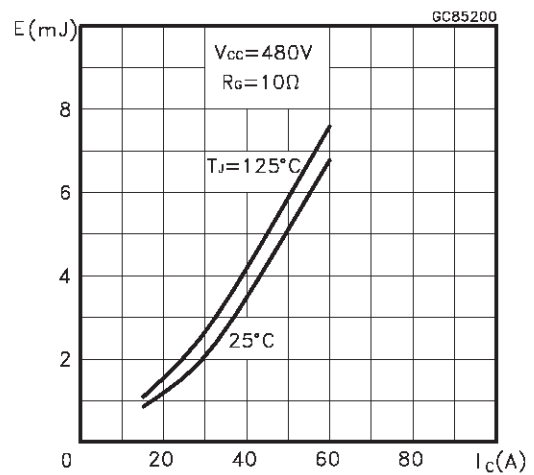
Total Switching Losses vs Gate Resistance



Total Switching Losses vs Temperature



Total Switching Losses vs Collector Current



Switching Off Safe Operating Area

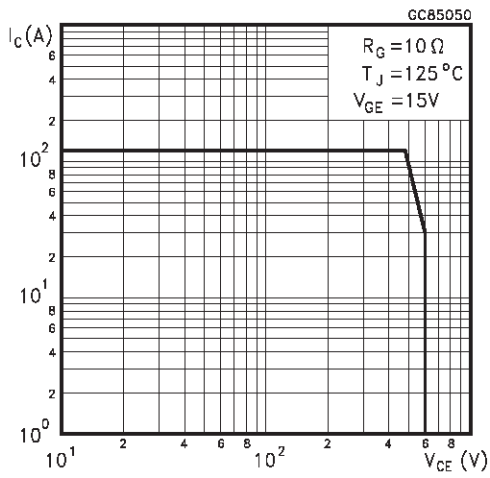


Fig. 1: Gate Charge test Circuit

Diode Forward Voltage

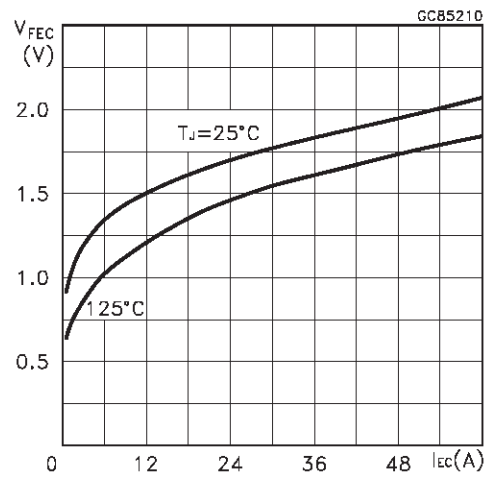


Fig. 2: Test Circuit For Inductive Load Switching

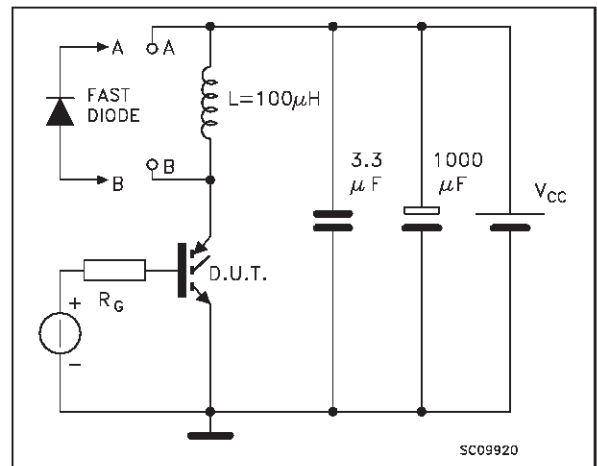
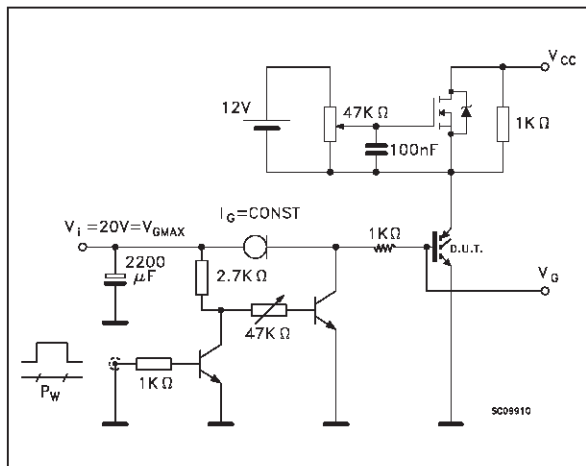
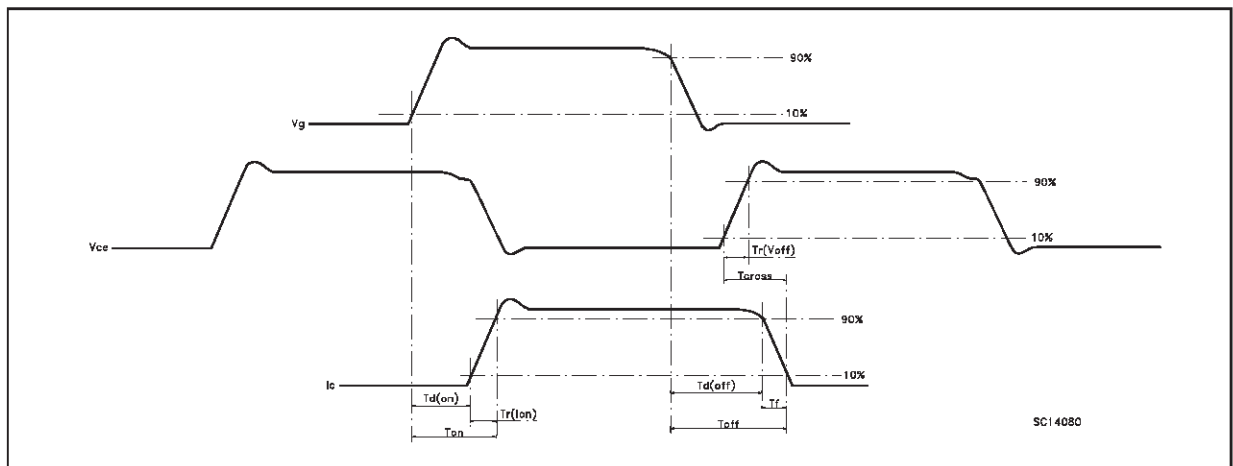
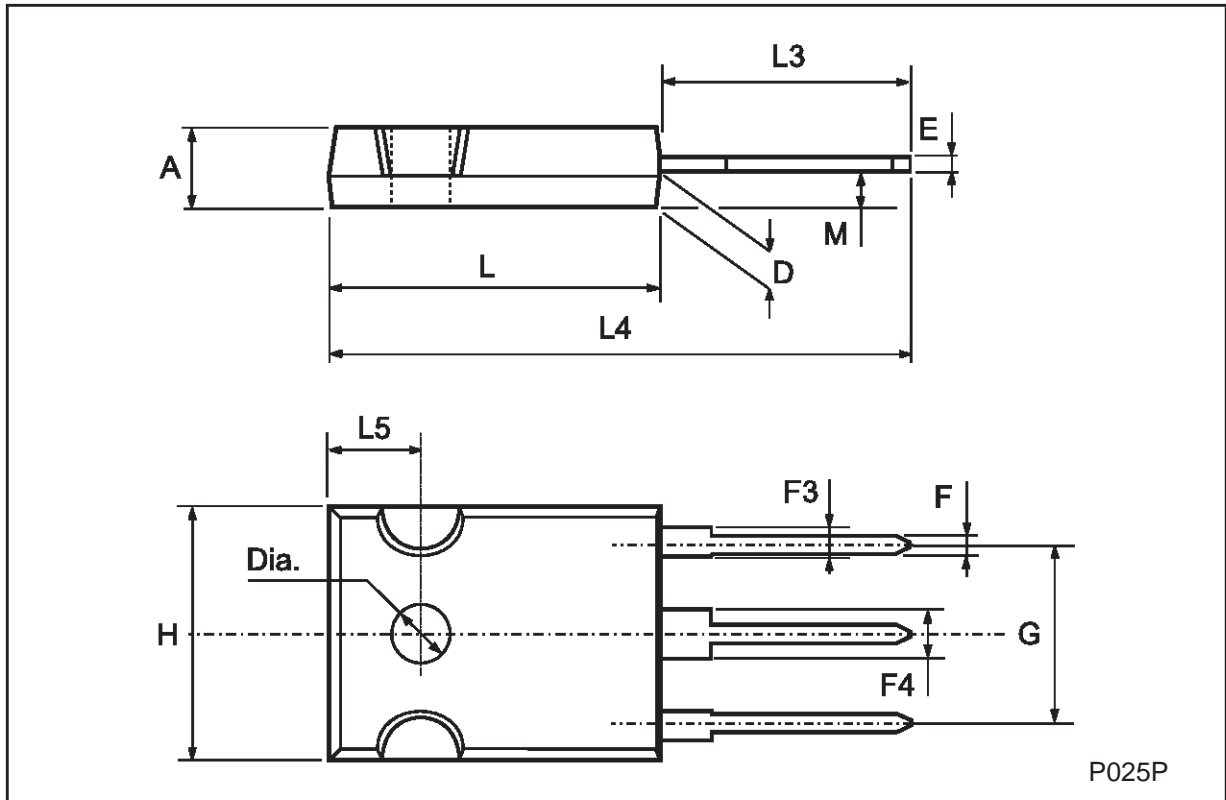


Fig. 3: Switching Waveforms



TO-247 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	4.7		5.3	0.185		0.209
D	2.2		2.6	0.087		0.102
E	0.4		0.8	0.016		0.031
F	1		1.4	0.039		0.055
F3	2		2.4	0.079		0.094
F4	3		3.4	0.118		0.134
G		10.9			0.429	
H	15.3		15.9	0.602		0.626
L	19.7		20.3	0.776		0.779
L3	14.2		14.8	0.559		0.582
L4		34.6			1.362	
L5		5.5			0.217	
M	2		3	0.079		0.118



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